Department of Physics

**Indian Institute of Technology Patna**

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**Requisition form for Scanning Probe Microscopy**

1. USER and PAYMENT DETAILS

|  |  |  |  |
| --- | --- | --- | --- |
| Name, Affiliation | Department/Organization (In case of outside IIT P, give full postal address) | Contact details(phone number and e-mail id) | Payment confirmation(Please see the terms and conditions, to know about any additional charges for estimation) |
|  |  |  | Amount Paid:DD number/Transaction Reference:Date:Bank: |

1. SAMPLE DETAILS

|  |  |
| --- | --- |
| **No of Samples with sample ID (s):** |  |
| Nature of sample | Type of sample: Thin film/Dispersion on a flat surfaceIs the sample optically smooth? Yes/No If No, mention optical roughness of sample: Any other sample info relevant to SPM… |

1. EXPERIMENTAL DETAILS REQUIRED

|  |
| --- |
| 1. Imaging Type: AFM/MFM/CSAFM/EFM
2. Imaging mode: Contact/Non-Contact
3. Scan Size(s)\*:
4. Any other specific requirement:

\* if not clearly mentioned, scan will be done for 2x2 micron square at arbitrary location |

Signature of the user

Name & Signature of the Supervisor

Signature of HoD, user department

(With date and official seal)

FOR OFFICE USE ONLY

1. SLOT ALLOTMENT DETAILS

Job Order Number:

Assigned date and time of execution: No. of slots allotted:

Signature of staff operator/in-charge Signature of Faculty in-charge

**Terms and Conditions for using the Facilities**

1. The mentioned charges are **excluding any applicable GST.**
2. The charges mentioned are **per slot of one hour** unless otherwise mentioned in the table mentioning analytical charges
3. Samples should be ready to use for/in/with the instrument used in the experiment.
4. User may contact the concerned operator for the experiment specific preparation/treatment of sample.
5. The charges mentioned are only for measurement and providing the raw data (in the format possible with the instrument) thereafter. No analysis/software compatibility of data can be claimed later. For consultancy on data analysis, the user may contact the experts separately through head of the department.
6. Measurements are subject to the corresponding instrument being in working condition. The status of each instrumental facility will be updated regularly.
7. In case of the measurement remains incomplete due to malfunctioning or any unforeseen situation, the user will be notified. Depending upon user’s discretion, either the payment received will be returned or the measurement will be carried out after the instrument becomes functional (maximum waiting period also may be informed by user).

**Analytical charges related to experiments performed with SPM**

|  |  |  |
| --- | --- | --- |
| Name of the facility | Measurement type | Analytical charges (in INR, per one hour) |
| Users from external academic institutes | Users from Industries /R & D laboratories |
| SPM | AFM imaging only | 1500 | 4000 |
| User has to send the respective tip. Alternatively, additional amounts of INR 2000 will be charged for issuing a normal contact/non-contact mode tip subject to availability. |
| CSAFM imaging + IV curve | 2500 | 6000 |
| User has to send the respective tip. Alternatively, additional amounts of INR 5000 will be charged for issuing a Au/Pt coated contact mode tip subject to availability. |
| Any other specific requirement with SPM | To be estimated after mutual discussion |

\*For any specific customized measurement/testing, the analytical charges can be estimated in consultation with Physics department.